1375 1375	Subclass	SUE CLASSIFICATION
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PATENT NUMBER

U.S. **UTILITY** Patent Application

SCANNED CO.I.P.E.	PATENT DAT		

APPLICATION NO. 09/911375	CONT/PRIOR	438714	SUBCLASS	ART UNIT	EXAMINER
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		ISSUING C	CLASSIFICATION
ORIGINA	IL .		CROSS REFERENCE(S)
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DISCLAIMER	DRAWINGS			CLAIMS ALLOWED		
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.	
The term of this patent subsequent to(date)		<u> </u>		NOTICE OF AL	LOWANCE MAILED	
has been disclaimed.	(Assistant Examiner) (Date)					
The term of this patent shall not extend beyond the expiration date						
of U.S Patent. No.				ISS	UE FEE	
				Amount Due	Date Paid	
	(Primary Examiner)		(Date)			
The terminalmonths of this patent have been disclaimed.				ISSUE BAT	CH NUMBER	
	(Legal instruments Examiner) (Date)		(Date)		·	
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